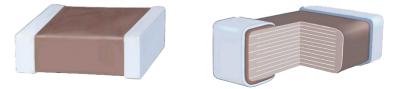


Multilayer Ceramic Chip Capacitors

江苏芯声微电子科技有限公司

Jiangsu Holy Ram Electronics Technology Limited



CAI Series (Automotive Grade)

Temp. Range -55℃125℃ -55℃125℃
Cap.Tolerance ±15% ±30ppm/°C

-



PRECAUTIONS FOR USE

Please attach the purchase specification before using this product.

SAFETY INFORMATION

Please pay attention to safety precautions when using this product.

Limitation of Applications

Please contact us before using our products for the applications listed below which require especially high reliability for the prevention of defects which might directly cause damage to the third party's life, body or property.

①Aircraft equipment	②Aerospace equipment	③Undersea equipment	④Power plant control equipment
SMedical equipment	⑥Transportation equipment(vehicles,trains,ships,etc.)	⑦Traffic signal equipment
⑧Disaster prevention / cri	me prevention equipment	③Data-processing equipment	@Application of similar complexity and/or

Methods of transportation and storage

1.Transportation:

Packaged products suitable for modern transportation, in the process of transportation to prevent rain and acid and alkali corrosion, gravity throwing and force extrusion.

2.Storage:

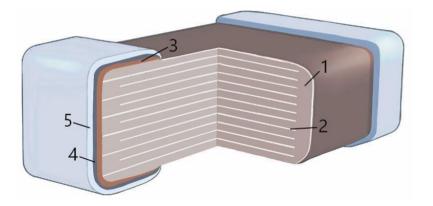
The storage period to ensure good weldability of the product is one year from the date of production. Do not open the braid before use of the product (in the case of packaging and delivery). After the braid is opened, the product should be used within three months. storage temperature: $0^{\circ}C \sim 35^{\circ}C$

Storage relative humidity: <70%

Multilayer Ceramic Chip Capacitors

- > complies with AEC-Q200 standard
- > conforms to the MSL class :MSL 1
- complies with vehicle regulation J-STD-020D
- > High reliability and equipment reliability
- > Pass 100% six-sided photosynthesis test

Product Structure Diagram



Applicatiopn

- car audio and video
- Body electronics
- High reliability
- Industrial applications

Serial number	Designation
1	Dielectric ceramics
2	Inner electrode (nickel)
3	Outer electrode (copper)
4	Nickel layer
5	Tin layer



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Product model naming rules

EX:	<u>C</u>	AI	<u>0402</u>	<u>X7R</u>	<u>104</u>	K	5	00) (3	T					
	(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8	8)	(9)					
(1)	C:MLC	CC				Сар.	.>=10p	F:								
(2) Application	AI:Aut	tomotive	9		(5)		Two×1									
	Co	ding	inch	Size(mm)	Capacitance	104=	=10×10	^4=	=100nF							
	00	DR4	008004	0201	value	Value 123=12×10^3=12nF										
	0.	1R5	01005	0402		Cap.	. < 10pF	: R	30=0.3p	oF, 1	R0=1pF	:				
	02	201	0201	0603	(6)	A: =	±0.05pF	5pF B: ±0.1		рF	oF C: ±0.2		D:	±0.5pF	F:	±1.0%
(3) Sizo	0402 0402 1		1005	Capacitance Tolerance	G: :	±2%	J: ±5%			K: ±10)%	M:	±20%	Z:	80/-20%	
Size (L*W)	0	603	0603	1608		2R5:	:2.5	4R():4.0	6R3	:6.3	100:10		160:16		250:25
()	0	805	0805	2012	(7) Rate voltage	350:	:35	500):50	630	:63	800:80		101:100		201:200
	17	206	1206	3216	Vdc	251:	:250	401	:400	451:	450	501:500)	631:630		102:1000
	1	210	1210	3225		202:	2000	252	2:2500	302:	3000	402:400	00			
	18	808	1808	4520	(8)	A:0.1	10	B:0	.13	C:0.	18	D:0.20		E:0.30		F:0.45
	18	812	1812	4532	Thickness	G:0.	.50	H:C).60	J:0.8	30	K:0.85		L:1.15		M:1.25
(4)					(mm)	N:1.	.60	P:1	.90	Q:2	.00	R:2.50				
Temperature Characteristic		X7R			(9) Packing	T: Fi	nished p	oro	duct pa	ckagi	ng (7″	Reel)				

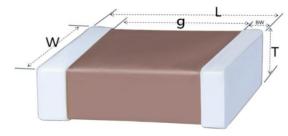
Size & Packing Specifications

Generally, a Φ180mm (7") tray is used for packing.

Each 5 disks is packed into a box, and each 12 boxes is a whole box.

		Size (n	nm)		Packin	ng (7″)	
规格	Length	Width	Thickness	g	Number (star)	Method	
0201	0.60±0.03	0.30±0.03	0.30±0.03	0.20	15,000	Paper tape	
0402	1.00±0.05	0.50±0.05	0.50±0.05	0.30	10,000	Paper tape	
0603	1.60±0.10	0.80±0.10	0.80±0.10	0.30	4,000	Paper tape	
0805	2.00+0.20	1 25 + 0 20	0.85±0.20	0.50	4,000	Paper tape	
	2.00±0.20	1.25±0.20	1.25±0.20	0.50	3,000/2,000	Plastic tape	
			0.85±0.20		4,000	Paper tape	
1206	3.20±0.20	1.60±0.20	1.25±0.20	1.00	3,000/2,000	Plastic tape	
			1.60±0.20		2,000	Plastic tape	
			1.25±0.30		3,000		
1210	3.20±0.40	2.50±0.30	1.60±0.30	1.00	2,000	Plastic tape	
			2.50±0.30		1,000		

* Plz refer to the single specification for details





Capacitance Range [COG] 0402~0805

Size	Thick	RV	1pF			10pF						100p	F					1nF						10nF
(inch)	(Code)	(Vdc)	1R0	2R2	4R7	100	150	220	330	470	680	101	151	221	331	471	681	102	152	222	332	472	682	103
0402	0.50	25																						
0402	(G)	50																						
	0.80	25																						
0603	1 1	50																						
	(L)	100																						
	0.60	25																						
	(H)	50																						
0805	0.85	25																						
0805	(K)	50																						
	1.25	25																						
	(M)	50																						

[X7R] 0201~1210

35

Size	Thick RV		150p	F			1nF				15nF			100n	F		1uF			10uF
(inch)	(Code)	(Vdc)			331	681		152	332	682		333	473		224	474	105	225	475	
0201	0.30	16																		
0201	(E)	25																		
		6.3																		
	0.50	16																		
0402	(G)	25																		
	(0)	50																		
		100																		
		10																		
	0.80	16																		
0603	(J)	25																		
	(2)	50																		
		100																		
		16																		
	0.85	25						_				_								
	(K)	50												1						
		100					_													
		250					1													<u> </u>
0805		6.3																		
		10 16																		
	1.25	25																		
	(M)	50																		
		100												:						
		250																		
		25																		
1206	1.60	50																		
	(N)	100																		
	2.00	50																		
	(Q)	100																		
1210	1210 (Q) 2.50	25																		
	(R)	50																		

No	ltem	Specification		Test Metho	d(Ref.	Standard:AEC—Q200)					
1	Pre-and-Post- Stress Electrical Test										
		Appearance	No defects or abnormalities.	Mounting m	ethod	Solder the capacitor on th	ne test substrate				
	High	Cap. Change	Plz refer to the single specification	Test Tempe	erature	150+/-3 ℃					
2	Temperature Exposure (Storage)	Q or D.F.	Within the specified initial value	Test Time		1000+/-12h					
		I.R.	Within the specified initial value	Post-treatm	ent	Let sit for 24+/-2hours at room temperature, then measure.					
				Mounting method		Solder the capacitor on th	ne test substrate				
		Appearance	No defects or abnormalities.	Pre-treatme	ent	Perform a heat treatment at 150+0/-10°C for 1hour and then let sit for 24+/-2hours at room temperature, then measure.					
				Cycles		1000 cycles					
		Cap. Change	Plz refer to the single specification	Temperatur	e Cyclii	ng:					
3	Temperature Cycling			Step	Temp	erature (°C)	Time (min)				
	e young			1	Min. (Operating Temp.+0/-3	30+/-3				
		Q or D.F.	Within the specified initial value	2	Room	Temperature	1				
				3 Max.		Operating Temp.+3/-0	30+/-3				
				4	Room	Temperature	1				
		I.R.	Within the specified initial value	Post-treatment		Let sit for 24+/-2hours at room temperature, then measure					

No	Item	Specification		Test Method(Ref.	Standard:AEC—Q200)
4	DPA	Appearance	No defects or abnormalities.	Per EIA-469	
				Mounting method	Solder the capacitor on the test substrate
		Appearance	No defects or abnormalities.	Test Temperature	+25℃ to +65℃
				Test Humidity	80% to 98% R.H.
		Cap. Change	Plz refer to the single specification	Test Time	Apply the 24h treatment shown below, 10 consecutive times.
5	Moisture			Temperature and H	Humidity cycle:
5	Resistance	Q or D.F.	Within the specified initial value	80 75 76 80 80 80 80 80 80 80 80 80 80 80 80 80	
		I.R.	Within the specified initial value	Post-treatment	Let sit for 24+/-2hours at room temperature, then measure
				Mounting method	Solder the capacitor on the test substrate
		Appearance	No defects or abnormalities.	Test Temperature	85+/-3 ℃
				Test Humidity	80% to 85% R.H.
		Cap. Change	Plz refer to the single specification	Test Time	1000+/-12h
6	Biased Humidity	Q or D.F.	Within the specified initial value	Test Voltage	1. Rated voltage (not exceeding 630V) 2. Apply 1.5V (silver electrode) Connect the 100KΩ resistor
				Charge/discharge current	50mA max
		I.R.	Within the specified initial value	Post-treatment	Let sit for 24+/-2hours at room temperature, then measure

No	Item	Specification		Test Method(Ref.	Standard:AEC—Q200)			
		Appearance	No defects or abnormalities.	Mounting method	Solder the capacitor on the test substrate			
		Cap. Change	Plz refer to the single specification	Test Temperature	Maximum Operating Temperature +/-3°C			
		Q or D.F.	Within the specified initial value	Test Time	1000+/-12h			
7	Operational Life	Q 01 D.F.	within the specified initial value	Test Voltage (R.V.)	PIz refer to the single specification			
				Charge/discharge current	50mA max			
		I.R.	Within the specified initial value	Post-treatment	Let sit for 24+/-2hours at room temperature, then measure			
8	Appearance	No defects or a	bnormalities.	Visual inspection				
9	Dimension	Shown in Dime	nsion.	Using Measuring instrument of dimension				
		Appearance	No defects or abnormalities.					
	Resistance to	Cap. Change	Within the specified initial value					
10	Solvents	Q or D.F.	Within the specified initial value	Per MIL-STD-202 Method 215 (Only for the Mark po				
		I.R.	Within the specified initial value					
		Appeorance	No defects or abnormalities.	Mounting method	Solder the capacitor on the test substrate			
		Appearance	no delects of abhormalities.	Waveform	Half-sine			
	Mashaniasi	Cap. Change	Within the specified initial value	Peak value	1500g			
11	Mechanical Shock	Q or D.F.	Within the specified initial value	Holding Time	0.5ms			
				Velocity change	4.7m/s			
		I.R.	Within the specified initial value	Shocks directions and times	Three shocks in each direction should be applied along 3 mutually perpendicular axes of the test specimen (18 shocks).			

No	ltem	Specification		Test Method(Ref.	Standard:AEC—Q200)
		Appearance	No defects or abnormalities.	Mounting method	Solder the capacitor on the test substrate
		Cap. Change	Within the specified initial value	Kind of Vibration	A 10Hz ~ 2000Hz ~ 10Hz
12	Mechanical	Q or D.F.	Within the specified initial value	Vibration Time	20min
	Vibration	יו. שוט אָ		Total amplitude	1.5mm
		I.R.	Within the specified initial value	Vibration directions and time	This motion should be applied for 12 items in each 3 mutually perpendicular directions (total of 36 times).
		Appearance	No defects or abnormalities.	Test Method	Solder bath method
		Cap. Change	Within the specified initial value	Kind of Solder	Sn-3.0Ag-0.5Cu(Lead Free Solder)
13	Resistance	Q or D.F.	Within the specified initial value	Test Temperature	260+/-5℃
	to Soldering Heat			Test Time	10+/-1s
		I.R.	Within the specified initial value	Post-treatment	Let sit for 24+/-2hours at room temperature, then measure.
		Appearance	No defects or abnormalities.	Per AEC-Q200-00	6 KV DC FAIL PASS
14	ESD	Cap. Change	Within the specified initial value		ASS FAIL PASS FAIL PASS FAIL PASS FAIL PASS FAIL PASS FAIL PASS FAIL PASS
		Q or D.F.	Within the specified initial value	500 V DC 1 kV DC FAIL PASS	2 kV DC DC DC DC DC DC DC DC DC DC
		I.R.	Within the specified initial value	electrostatic voltag	ed according to the highest level of ge under static test. Flow chart of passive anti-static test act discharge, AD = air discharge)

No	Item	Specification		Test Meth	od(Ref. Stand	lard:A	.EC—Q200)			
				Pre-treatm	ent	Perfo	rm a heat treatment at 155°C			
				Flux		Soluti	on of rosin ethanol 25(mass)%			
				Kind of So	der	Sn-3.0Ag-0.5Cu(Lead Free Solde				
15	Solderability (a)	95% of the term continuously	ninations is to be soldered evenly and	Solder Ter	anaratura	Sn-3.0Ag-0.5Cu solder solution at 245+/-5 $^{\circ}$ C				
				Immersion	time	5+0/-0	0.5s			
				Immersion and emersion rate			5mm/s			
		Capacitance	Shown in Rated value	Test Temp	erature		25 ℃			
				Test Frequ	ency		1.0+/-0.1MHz			
		Q or D.F.	Plz refer to the single specification	Test Voltag	ge		1.0±0.2Vrms			
				Test Temperature			25 ℃			
		I.R.	Within the specified initial value	Test Voltag	ge		Plz refer to the single specification			
		1.13.		Charging 1	īme		1min			
				Charge/discharge current			50mA max			
	Electrical			Material	Rate Voltag	е	Test Voltage			
16	Characterization				RV≤50V		300% RV			
					50V < RV≤1	00V	250% RV			
				C0G	100V < RV≤	250V	200% RV			
		Voltage proof	No defects or abnormalities.		250V < RV≤	500V	150% RV			
		Voltage proof			500V < RV≤1	V000	130% RV			
					RV≤100V		250% RV			
				X7R	100V < RV≤250V		200%RV			
					250V < RV≤630V		150% RV			
					630V < RV≤1000V					

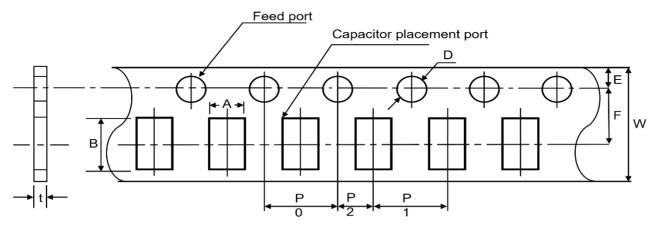
No	ltem	Specification		Test Method(Re	f. Standard:AEC—Q200)
				Mounting Method	Solder the capacitor on the test substrate
		Appearance	No defects or abnormalities.	Test Method	Apply force at 1mm/s to bend it, with a jig radius of 340mm
		Cap. Change	Plz refer to the single specification	Flexure Holding Time	C0G:3mm X7R:2mm 60s
17	Board Flex	Q or D.F.	Within the specified initial value		04.5 VISCIA7 尺寸 a b c 40 0201 0.3 0.9 0.3 0402 0.5 1.5 0.6 0603 0.6 2.2 0.9
		I.R.	Within the specified initial value		1206 2 4.4 1.7
	Terminal Strength	Appearance	No defects or abnormalities.	Mounting method	Solder the capacitor on the test substrate
		Cap. Change	Within the specified initial value	keep applying 17.7N (1.8Kg) *0402 Apply 2N	
18		Q or D.F.	Within the specified initial value	Applied Force	*0201 Apply 1N Note: Apply the force gradually so as not to impact the parts under test
		I.R.	Within the specified initial value	Holding Time	60+1s
19	Beam Load Test	The tolerance should exceed the following values:Size L<2.5mm		Speed supplied t Placement diagra [Size L≤2.5mm]	he Stress Load 0.1mm/s am: [Size L≧3.2mm]
					<mark>←→</mark> 0.6L Fig. d.

No	ltem	Specification	Test Meth	od(Ref. Stand	(Ref. Standard:AEC—Q200)		
	Temperature Characteristics of Capacitance	Cap. Change f	The nominal value of the temperature coefficient is shown in the rating. The	The capacitance change should be measured after 5 min at each specified temp. stage. Capacitance value as a reference is the value in "*" marked step.			
			change of capacitance at reference temperature is shown in Table A.	Cap. Change		Tolerance changes are calculated by dividing the difference between the maximum and minimum values	
20				Test Volta	ge	Less than 1.0Vrms (Refer to the individual data sheet)	
				Temperat	ure Step: (A)	
				Step	Temperat	ture	
		C0G: ± 30ppm /°C		1	Ref. Tem	perature:+/-2	
		X7R: ± 15%		2	Min. Ope	rating Temp.:+/-3	
		X/IX. ± 13/0		3*	Ref. Tem	perature:+/-2	
				4	Max. Ope	erating Temp.:+/-3	
				5	Ref. Tem	perature:+/-2	

Product Packaging

At present, the most common way of packaging is to carry coil packaging. A coil with a diameter of 180mm (7") can contain 1000~20000 capacitors, or coil packaging can be carried out according to customer requirements.

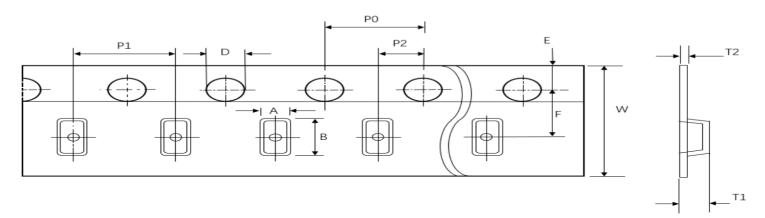
1. Tape Size



	01005	0201	0402	0603	0805	1206
	(0402)	(0603)	(1005)	(1608)	(2012)	(3216)
P1	2.0	00±0.05(1.0 ±0.0)5)		4.00±0.10	
P0		4.00±0.10			4.00±0.10	
P2		2.00±0.05		2.00±0.05		
А	0.25±0.02	0.38±0.03	0.62±0.05	1.00±0.01	1.55±0.10	2.05±0.10
В	0.46±0.02	0.68±0.03	1.12±0.05	1.90±0.10	2.30±0.10	3.60±0.10
W		8.00±0.30		8.00±0.30		
E	1.75±0.10			1.75±0.10		
F	3.50±0.05			3.50±0.05		
D	φ1.50+0.10/-0.03			φ1.50+0.10/-0		
t	0.25±0.02 0.35±0.03 (0.60±0.05	1.1Below		



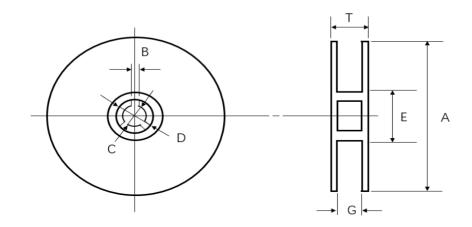
2. Plastic Size



	0603 (1608)	0805 (2012)	1206 (3216)	1210 (3225)
P1	4±0.1	4±0.1	4±0.1	4±0.1
P0	4±0.1	4±0.1	4±0.1	4±0.1
P2	2±0.05	2±0.05	2±0.05	2±0.05
A	1.2±0.2	1.45±0.2	1.9±0.2	2.8±0.2
В	2.0±0.2	2.3±0.2	3.5±0.2	3.6±0.2
W	8±0.3	8±0.2	8±0.2	8±0.2
E	1.75±0.1	1.75±0.1	1.75±0.1	1.75±0.1
F	3.5±0.05	3.5±0.05	3.5±0.05	3.5±0.05
D	1.5 (+0.1/-0.0)	1.5 (+0.1/-0.0)	1.5 (+0.1/-0.0)	1.5 (+0.1/-0.0)
T1	1.4 max	2.5 max.	2.5 max.	2.5 max.
T2	0.25±0.1	0.305±0.1	0.30±0.1	0.30±0.1



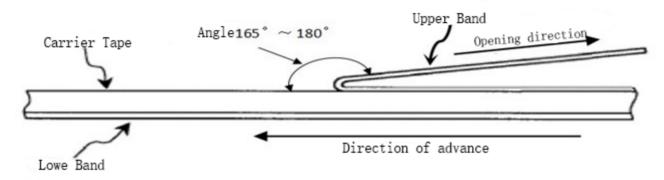
3. Disk Size



Disk Size	A	B	C	D	E	G	T
	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)
7″Reel	Ф178±2.0	2.0±0.5	Φ13±1.0	Φ21±0.8	Φ50 或更大	10±1.0	13±1.0

4. Instructions for use of reel tape

When the finished product is in use, the upper band (film) is at a speed of 300 ± 10 mm/min, an Angle of $165^{\circ} \sim 180^{\circ}$ (as shown below), and the peeling strength is $0.1N \sim 0.7N$ ($10g.f \le$ peeling force $\le 70g.f$).





Precautions for use

Multi-layer Ceramic Chip Capacitors(MLCC) may have short circuit or open circuit under the harsh working environment beyond the use frequency described in this letter of admission or related instructions, or under the action of external mechanical force overpressure. Or it may smoke, burn or even explode, so when using, we should first consider to follow the relevant instructions in this acknowledgement, if there is anything unclear, please contact our technical department, Quality Control Department or production Department.

1. The amount of solder used in welding

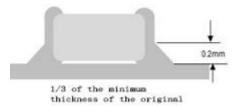
A. Too much solder will cause capacitor damage due to excessive pressure at the capacitor end.



B.Too little solder fixed force is insufficient, may cause capacitor chip and line contact is poor.



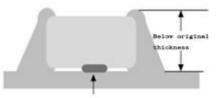
2.Recommended amount of solder:A. Optimal amount of solder for reflow welding



C. The optimal amount of solder used for repair with soldering iron



B. Optimum amount of solder for wave soldering



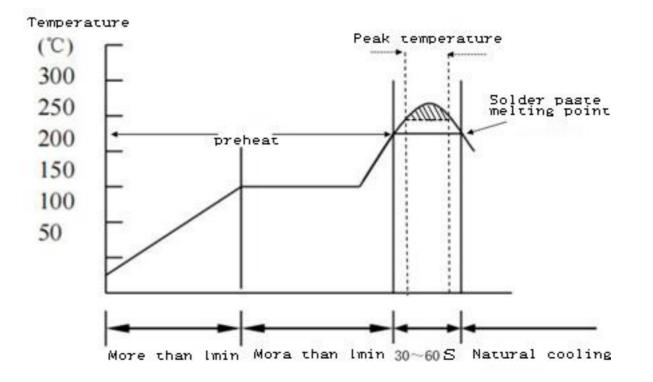
Binding agent

A-IPF

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3. Recommended welding temperature curve:

Reflow welding

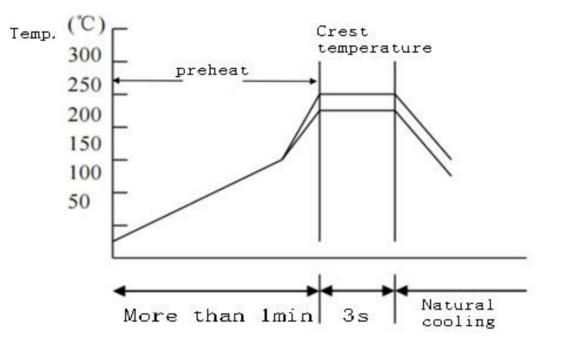


Solder type	Pb-Sn welding	Lead-free welding
Peak temperature	230°C ~ 250°C	240°C ~ 260°C
Peak time	3s ~ 10s	3s ~ 10s

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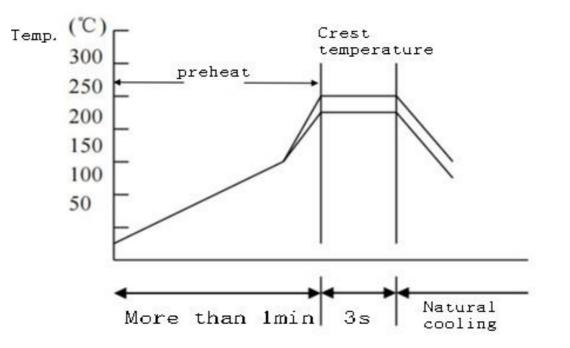
Solder type	Pb-Sn welding	Lead-free welding
Peak temperature	230°C ~ 260°C	240°C ~ 270°C
Peak time	Within 3s	Within 3s

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Hand welding

Manual welding is easy to cause micro-cracking or partial cracking of porcelain because of uneven local heating of capacitor. Therefore, the use of electric iron manual welding should be carefully operated, and the choice of the tip of the electric branding iron and tip temperature control should be more careful.



Preheat	Temperature	Power	Diameter	Time	Tin paste	Notice
△≤130°C	≤350°C	≤20W	Recommended 1mm	≤3s	≤1/2 Capacitance height	Do not contact the iron head directly with the ceramic body

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Multilayer Ceramic Chip Capacitors

版本	修订日期	修订内容叙述
CAI-A-2023-01	2023/2/25	Initial issue
CAI-A-2023-02	2023/6/25	1. Update the tolerance range legend
		2. Update the packaging quantity
		3. Update the Feature content

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